

Notice of References Cited

Application/Control No.

10/551,476

Applicant(s)/Patent Under
Reexamination
JOHNS ET AL.

Examiner

DOUGLAS MC GINTY

Art Unit

1796

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U.S. PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Name	Classification
*	A	US-3,330,672 A	07-1967	HARRY KROLL et al.	106/3
*	B	US-3,518,098 A	06-1970	COX BERNARD CARLTON et al.	106/3
*	C	US-6,165,284 A	12-2000	Shubkin, Ronald L.	134/38
	D	US-			
	E	US-			
	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

FOREIGN PATENT DOCUMENTS

*		Document Number Country Code-Number-Kind Code	Date MM-YYYY	Country	Name	Classification
	N	DE 3905850 A1	08-1990	Germany		
	O	JP 59215490 A	12-1984	Japan	NAGANO et al.	
	P	JP 52111430 A	09-1977	Japan		
	Q	DE 1932524 A	04-1970	Germany		
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*		Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)
	U	Reg. no. 106-94-5, Nov. 16, 1984.
	V	Reg. no. 2885-00-9, Nov. 16, 1984.
	W	Reg. no. 2917-26-2, Nov. 16, 1984.
	X	Reg. no. 10220-46-9, Nov. 16, 1984.

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
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	F	US-			
	G	US-			
	H	US-			
	I	US-			
	J	US-			
	K	US-			
	L	US-			
	M	US-			

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		Country Code-Number-Kind Code	MM-YYYY			
	N					
	O					
	P					
	Q					
	R					
	S					
	T					

NON-PATENT DOCUMENTS

*	Include as applicable: Author, Title Date, Publisher, Edition or Volume, Pertinent Pages)				
	U	Reg. no. 22811-02-5, Nov. 16, 1984.			
	V	Burleigh et al., "Tarnish Protection of Silver Using a Hexadecanethiol Self-Assembled Monolayer and Descriptions of Accelerated Tarnish Tests", Corrosion, 57, 12, Dec. 2001, 1066-1074.			
	W	Chang et al., "New normal-propyl bromide based cleaning technology for the electronics industry", Circuit World, 25, 4, 1999, 17 pages.			
	X				

*A copy of this reference is not being furnished with this Office action. (See MPEP § 707.05(a).)
Dates in MM-YYYY format are publication dates. Classifications may be US or foreign.